Application/Control No. 09/752,099 Examiner Kim T. Huynh Applicant(s)/Patent Under Reexamination CONNOR ET AL. Art Unit Page 1 of 1

Notice of References Cited

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,567,882	05-2003	Onagawa, Seiki	710/314
	В	US-			, <u></u>
	С	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	-	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	Ø				·	
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

NON-I ATENT BOOMENTO							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	·U						
	٧						
	w						
	×						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.